Specifications

Drawing No.	UKY1C-H1-15838-00[31]	1/11
Issued Date.	Jul, 15, 2015	

TO: Digi-Key

Note: In case of specification change, KYOCERA Part Number also will be changed.

Product Name	Quartz Crystal
Product Model	CX2520DB
Frequency	32000kHz
Customer Part Number	-
Customer Specification Number	-
KYOCERA Part Number	CX2520DB32000D0WZRC1
Remarks Pb-Free, RoHS Com	bliant, MSL 1

Customer Acceptance

Accept Signature	Approved Date	
	Department	
	Person in charge	

Seller KYOCERA Crystal Device Corporation (Sales Division) 6 Takeda Tobadono-cho, Fushimi-ku, Kyoto 612-8501 Japan TEL. No. 075-604-3500 FAX. No. 075-604-3501

Manufacturer

Crystal Units Division 5850, Higashine-Koh, Higashine-Shi, Yamagata 999-3701 Japan TEL. No. 0237-43-5611 FAX. No. 0237-43-5615

Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Crystal Device Corporation Field Application Engineering Section Crystal Units Division	T. Noritake	K. Yamazaki	T. Nitoube	Y. Kikuchi

Drawing No.	UKY1C-H1-15838-00[31]	2/11	
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Revision History

Description of revise	Date	Approved by	Checked by	Issued by
First Edition	Jul,15,2015	K. Yamazaki	T. Nitoube	Y. Kikuchi
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1. APPLICATION

This specification sheet is applied to quartz crystal "CX2520DB32000D0WZRC1"

2. KYOCERA PART NUMBER

CX2520DB32000D0WZRC1

3. RATINGS

Items	SYMB.	Rating	Unit	Remarks
Operating Temperature	Topr	-25 to +75	С°	
Storage Temperature range	Tstg	-40 to +85	C°	

4. CHARACTERISTICS

ELECTRICAL CHARACTERISTICS

Items		Electrical Specification					Remarks
	SYMB.	Min	Тур.	Max	Unit		
Mode of Vibration			Fundamenta	l			
Nominal Frequency	F0		32		MHz		
Nominal	T _{NOM}		+25		°C		
Temperature							
Load Capacitance	CL		8.0		pF		
Frequency	df/F					+25±3°C	
Tolerance							
Frequency	df/F					-25 to +75°C	
Temperature		-40.0		+40.0	PPM		
characteristics							
Frequency Aging						1 st year	+25±3°C
Rate							
Equivalent Series	ESR			50	Ω		
Resistance							
Shunt	C0			3.0	pF		
Capacitance							
Drive Level	Pd	0.01		100	μW		
Insulation	IR	500			MΩ	100V(DC)	
Resistance							

5. Measurement Condition

Drive Level

5.1 Frequency measurement

Measuring instrument : IEC P	I-Network Test Fixture
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- Load Capacitance
 - : 8.0pF : 10µW

5.2 Equivalent series resistance (ESR) measurement

Measuring instrument : IEC PI-Network Test Fixture

Load Capacitance : Ser

- Drive Level
- : Series : 10µW



6. APPEARANCES, PHYSICAL DIMENSION OUTLINE DIMENSION (not to scale)

%The font of marking is reference.

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7. RECOMMENDED LAND PATTERN (not to scale)

8. TAPING&REEL



8-2.Leader and trailer tape



8-3.Direction (The direction shall be seen from the top cover tape side)



8-4.Specification

- 1. Material of the carrier tape is either polystyrene or A-PET (ESD).
- 2. Material of the cover tape is polyester (ESD).
- 3. The seal tape shall not cover the sprocket holes and not protrude from the carrier tape.
- 4. Tensile strength of carrier tape: 10N or more.
- 5. The R of the corner of each cavity is 0.2RMAX.
- 6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
- 7. The orientation shall be checked from the top cover tape side as shown in 8-3.
- 8. Peeling force of cover tape: 0.1 to 1.0N.
- 9. The component will fall out naturally when cover tape is removed and set upside down.

Cover tape 165°~180° Career tape

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В

8-5.Reel Specification





φ180 Reel (3,000 pcs Max.)

Symbol	А	В	С	D
Dimension	φ180 +0/-3	φ60 +1/-0	φ13±0.2	φ21±0.8
Symbol	E	W	t	
Dimension	2.0±0.5	9±1	2.0±0.5	

(Unit:mm)

φ330 Reel (12,000 pcs Max.)

Symbol	A	В	С	D
Dimension	φ330±2.0	φ100±1.0	φ13±0.2	φ21±0.8
Symbol	E	W	t	
Dimension	2.0±0.5	9.5±0.5	2.2±0.1	

(Unit:mm)

9.Enviromental requirements

After conducting the following tests, component needs to meet below conditions.

Frequency: Fluctuation within +/-10 x 10^{-6}

CI: Fluctuation within +/-20% or 5 Ω whichever is larger

9.1	Resistance to Shock	Test condition 3 times natural drop from 100cm onto hard wooden board.
9.2	Resistance to Vibration	Test conditionfrequency: 10 - 55 - 10 HzAmplitude: 1.5mmCycle time: 15 minutesDirection: X,Y,Z (3direction),2h each.
9.3	Resistance to Heat	Test condition The quartz crystal unit shall be stored at a temperature of +85±2°C for 500h and subjected to room temperature for 1h before measurement.
9.4	Resistance to Cold	Test condition The quartz crystal unit shall be stored at a temperature of -40±2°C for 500h and subjected to room temperature for 1h before measurement.
9.5	Thermal Shock	Test condition The quartz crystal unit shall be subjected to 500 temperature cycles shown in table below, Then it shall be subjected to room temperature for 1h before mesurement. Cycle : $-40\pm2^{\circ}C$ (30min.) \rightarrow +25 $\pm2^{\circ}C$ (5min.) \rightarrow +85 $\pm2^{\circ}C$ (30min.) \rightarrow +25 $\pm2^{\circ}C$ (5min.)

9.6 Resistance to Moisture Test condition The quartz crystal unit shall be stored at a temperature of $+60\pm2^{\circ}$ C with relative humidity of 90% to 95% for 240 h. Then it shall be subjected to room temperature for 1h before measurement.

9.7 Soldering condition

1.) Type of solder

3.)

Material \cdots lead free solder paste Melting point \cdots +220±5°C

2.) Reflow temp.profile

	Temp [°C]	Time[sec]
Preheating	+150 to +180	150 (typ.)
Peak	+260±5	10 (max.)
Total		300 (max.)

Frequency shift : ± 2 ppm

Hand Soldering +350°C 3 sec max

4.) Reflow Times 2 times in below Reflow temp. profile





9.8 Bending Strength

Solder this product in center of the circuit board (40mm \times 100mm), and add deflection of 3mm.

Test board : t=1.6mm PUSH

UNIT : mm

10. Cautions for use

(1) Soldering upon mounting

There is a possibility to influence product characteristics when Solder paste or conductive glue comes in contact with product lid or surface.

- When using mounting machine
 Please minimize the shock when using mounting machine to avoid any excess stress to the product.
- (3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 5 times the ESR (Equivalent Series Resistance) of crystal unit.

11. Storage conditions

Please store product in below conditions, and use within 6 months. Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

12. Manufacturing location

Kyocera Crystal Device Corporation / Japan(Yamagata) Kyocera Crystal Device Corporation Shiga Yohkaichi Plant / Japan(Shiga) Kyocera Crystal Device (Thailand) Co., Ltd / Thailand(Lamphun)

13. Quality Assurance

To be guaranteed by Kyocera Crystal Device Quality Assurance Division

14. Quality guarantee

In case when Kyocera Crystal Device Corporation rooted failure occurred within 1year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1year of its delivery is waivered.

15. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.